PRS-L100-F500-SCD-I Silicon piezo-resistive sensing cantilevers

General description

Piezo-Resistive Sensing (PRS) probes are silicon cantilevers with a long-life single crystal diamond tip (SCD). Integrated piezoresistors are used for self-sensing the cantilever deflection. The piezo-resistors are integrated into a matched Wheatstone bridge to raise the sensitivity and compensate environmental thermal drift. Self-sensing readout technology makes laser adjustment obsolete and saves time during a cantilever change. The free space above the cantilever enables new applications and combination of AFM with various instruments. The SCD tip exhibits low surface energy, which prevents contamination when imaging sticky or biological samples. The cantilever chip is bonded to a small printed circuit board (PCB) with a small connector to enable a quick cantilever change. A cantilever PCB can be connected to a SCL's low-noise pre-amplifier via a SCL's flex PCB with its counter-part PCB.

Specifications		
Model	PRS-L100-F500-SCD-PCB	
Tip radius (apex)	<15 nm	
Tip height	1216 µm	
Tip material	Long life Single Crystal Diamond (SCD) <100> along tip axis	
Glue between tip and cantilever	non-conducting temp-stability: up to 70°C	
Resonant frequency	250750 kHz	
Spring constant	12330 N/m	
AFM mode	contact, tapping, non-contact	
Sensitivity*	13 µV/nm	
Force sensitivity*	4…330 nN/µV	
Length, width	100 ±5 μm, 48 ±2 μm	
Material	silicon cantilever, boron doped 1k Ohm piezo resistors, aluminium tracks	
Deflection sensing	on chip piezo-resistive bridge	
Actuator	external shaker	
Electrical connections	bonded to small PCB with connector (counter part PCB available) or optional bonding pads on chip	
Chip dimensions (h, w, l)	0.3 / 1.0 / 2.7 mm	
* not amplified (signal direc	t at the chip), 2.048 V bridge supply	

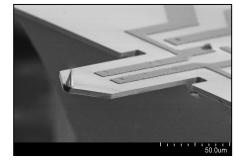
Applications:

- Integration on a standard AFM scanner •
- Direct use on an AFSEM[™] inside a SEM (<u>www.getec-afm.com</u>)
- Force sensing within a SEM, TEM, etc.; nano-indentation

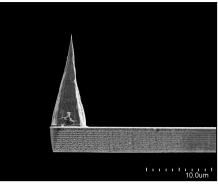
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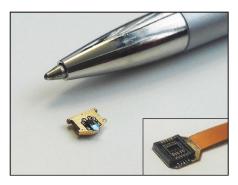




PRS-L100 cantilever with Al tracks for reading out the sensor signal



Side view of a SCD cantilever tip



Cantilever is bonded to a 6 x 4.5 mm PCB (height with connector 1.6 mm, with CP-PCB: 2.5 mm); left: counter part PCB



Hardware for amplified readout: Low-noise pre-amplifier (45x35 mm)

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PRSA-L300-F50-SCD-PCB

Silicon piezo-resistive sensing cantilevers

General description

Piezo-Resistive Sensing Active (PRSA) probes are silicon cantilevers with a long-life single crystal diamond tip (SCD). Integrated piezo-resistors and a heater are used for self-sensing and self-actuating the cantilever deflection. The piezo-resistors are integrated into a matched Wheatstone bridge to raise the sensitivity and compensate environmental thermal drift. Selfsensing readout technology makes laser adjustment obsolete and saves time during a cantilever change. The free space above the cantilever enables new applications and combination of AFM with various instruments. The SCD tip exhibits low surface energy, which prevents contamination when imaging sticky or biological samples. The cantilever chip is bonded to a small printed circuit board (PCB) with a small connector to enable a guick cantilever change. A cantilever PCB can be connected to a SCL's low-noise pre-amplifier via a SCL's flex PCB with its counter-part PCB.

Specifications		
Model	PRSA-L300-F50-SCD-PCB	
Tip radius (apex)	<15 nm	
Tip height	1216 µm	
Tip material	Long life Single Crystal Diamond (SCD) <100> along tip axis	
Glue between tip and cantilever	non-conducting temp-stability: up to 70°C	
Resonant frequency	3065 kHz	
Spring constant	115 N/m	
AFM mode	contact, non-contact	
Sensitivity*	12 µV/nm	
Force sensitivity*	0.5…56 nN/µV	
Length, width	300 ±5 μm, 110 ±3 μm	
Material	silicon cantilever, boron doped 1k Ohm piezo resistors, aluminium tracks	
Deflection sensing	on chip piezo-resistive bridge	
Actuator	external shaker or on chip heater (20-45 Ohm)	
Electrical connections	bonded to small PCB with connector (counter part PCB available) or optional bonding pads on chip	
Chip dimensions (h, w, l)	0.3 / 1.2 / 2.5 mm	
* not amplified (signal direct at the chip), 2.048 V bridge supply		

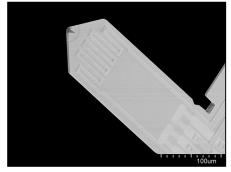
Applications:

- Integration on a standard AFM scanner
- Direct use on an AFSEM[™] inside a SEM (<u>www.getec-afm.com</u>)
- Force sensing within a SEM, TEM, etc.; nano-indentation

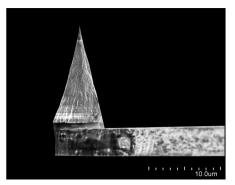
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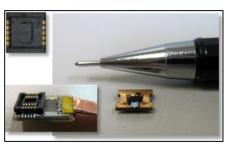




PRSA-L300-F50-SCD cantilever with Al tracks for reading out the sensor signal



Side view of a SCD cantilever tip



Cantilever is bonded to a 6 x 4.5 mm PCB (height with connector 1.6 mm, with CP-PCB: 2.5 mm); left: counter part PCB



Hardware for amplified readout: Low-noise pre-amplifier (45x35 mm)

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PRSA-L400-F30-SCD-PCB Silicon piezo-resistive sensing cantilevers

General description

Piezo-Resistive Sensing Active (PRSA) probes are silicon cantilevers with a long-life single crystal diamond tip (SCD). Integrated piezoresistors and a heater are used for self-sensing and self-actuating the cantilever deflection. The piezo-resistors are integrated into a matched Wheatstone bridge to raise the sensitivity and compensate environmental thermal drift. Self-sensing readout technology makes laser adjustment obsolete and saves time during a cantilever change. The free space above the cantilever enables new applications and combination of AFM with various instruments. The SCD tip exhibits low surface energy, which prevents contamination when imaging sticky or biological samples. The cantilever chip is bonded to a small printed circuit board (PCB) with a small connector to enable a quick cantilever change. A cantilever PCB can be connected to a SCL's low-noise pre-amplifier via a SCL's flex PCB with its counter-part PCB.

Specifications		
Model	PRSA-L400-F30-SCD-PCB	
Tip radius (apex)	<15 nm	
Tip height	1216 µm	
Tip material	Long life Single Crystal Diamond (SCD) <100> along tip axis	
Glue between tip and cantilever	non-conducting temp-stability: up to 70°C	
Resonant frequency	1540 kHz	
Spring constant	0.48.3 N/m	
AFM mode	contact, tapping, non-contact	
Sensitivity*	1 µV/nm	
Force sensitivity*	0.4…8.3 nN/μV	
Length, width	410 ±5 μm, 115 ±3 μm	
Material	silicon cantilever, boron doped 1k Ohm piezo resistors, aluminium tracks	
Deflection sensing	on chip piezo-resistive bridge	
Actuator	external shaker or on-chip heater (10 +/-2 Ohm)	
Electrical connections	bonded to small PCB with connector ready to connect to our counter part PCB	
Chip dimensions (h, w, l)	0.3 / 1.2 / 2.5 mm	
* not amplified (signal direc	t at the chip), 2.048 V bridge supply	

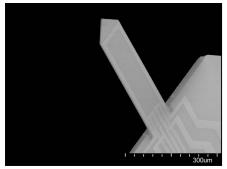
Applications:

- Integration on a standard AFM scanner
- Direct use on an AFSEM[™] inside a SEM (www.getec-afm.com)
- Force sensing within a SEM, TEM, etc.; nano-indentation

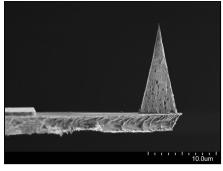
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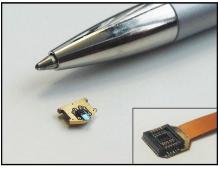




PRSA-L400-F30-SCD cantilever with AI tracks for reading out the sensor signal



Side view of a SCD cantilever tip



Cantilever is bonded to a 6 x 4.5 mm PCB (height with connector 1.6 mm, complete height connected to CP-PCB: 1.8 mm); left: counter part PCB



Hardware for amplified readout: Low-noise pre-amplifier (45x35 mm)

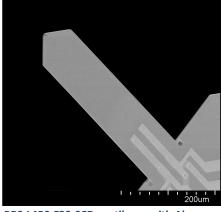
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PRS-L450-F30-SCD-P Silicon piezo-resistive sensing cantilevers

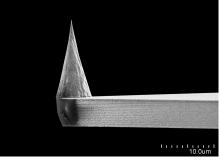


General description

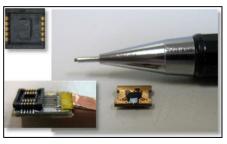
Piezo-Resistive Sensing (PRS) probes are silicon cantilevers with a long-life single crystal diamond tip (SCD). Integrated piezoresistors are used for self-sensing the cantilever deflection. The piezo-resistors are integrated into a matched Wheatstone bridge to raise the sensitivity and compensate environmental thermal drift. Self-sensing readout technology makes laser adjustment obsolete and saves time during a cantilever change. The free space above the cantilever enables new applications and combination of AFM with various instruments. The SCD tip exhibits low surface energy, which prevents contamination when imaging sticky or biological samples. The cantilever chip is bonded to a small printed circuit board (PCB) with a small connector to enable a quick cantilever change. A cantilever PCB can be connected to a SCL's low-noise pre-amplifier via a SCL's flex PCB with its counter-part PCB.



PRS-L450-F30-SCD cantilever with AI tracks for reading out the sensor signal



Side view of a SCD cantilever tip



Cantilever is bonded to a 6 x 4.5 mm PCB (height with connector 1.6 mm, with CP-PCB: 2.5 mm); left: counter part PCB



Hardware for amplified readout: Low-noise pre-amplifier (45x35 mm)

Contact: **Fabian Edlinger** Phone: +43 660 4424 871 fabian.edlinger@c-sense.at Leaflet version: 2024-03-11

Specifications	
Model	PRS-L450-F30-SCD-PCB
Tip radius (apex)	<15 nm
Tip height	1216 µm
Tip material	Long life Single Crystal Diamond (SCD) <100> along tip axis
Glue between tip and cantilever	non-conducting temp-stability: up to 70°C
Resonant frequency	1448 kHz
Spring constant	0.524 N/m
AFM mode	contact, non-contact
Sensitivity*	12 µV/nm
Force sensitivity*	0.2524 nN/μV
Length, width	450 ±5 μm, 100 ±3 μm
Material	silicon cantilever, boron doped 1k Ohm piezo resistors, aluminium tracks
Deflection sensing	on chip piezo-resistive bridge
Actuator	external shaker
Electrical connections	bonded to small PCB with connector (counter part PCB available) or optional bonding pads on chip
Chip dimensions (h, w, l)	0.3 / 1 / 2.6 mm
* not amplified (signal dired	t at the chip), 2.048 V bridge supply

Applications:

- Integration on a standard AFM scanner
- Direct use on an AFSEM[™] inside a SEM (www.getec-afm.com)
- Force sensing within a SEM, TEM, etc.; nano-indentation

What about your application? Contact us!

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